OCT 20 2006 Sheet 1 of 1 ATTY. DOCKET NO. SERIAL NO. FÖRM PTO-1449 DEPARTMENT OF COMMERCE TENT AND TRADEMARK OFFICE 60091.00305 10/829,424 APPLICANT LIST OF REFERENCES CITED BY APPLICANT Ari TIKKA et al. FILING DATE GROUP (Use several sheets if necessary) April 22, 2004 2621

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